



NSI AIN Templates





AT50-AX

Sapphire

Wafer Diameter	50.3mm
Orientation (c->m)	+0.2
Backside Roughness	Fine Ground

AlN

Orientation (major flat)	m-plane (AlN)
.....	
Thickness (measurement by whitelight)	
Avg	0.5 $\mu\text{m} \pm 0.05 \mu\text{m}$
(σ /Avg)	< 2%
.....	
Crystal Quality (FWHM)	
[002] XRD Linewidth	< 100 arcsec
[102] XRD Linewidth	< 340 arcsec
.....	
Transmission	>85% (@ 280 nm)
.....	
Exclusion Zone	3 mm
.....	
Surface Morphology	
AFM (R_z)	< 1 nm



Nitride Solutions Inc.

AT100-AX

Sapphire

Wafer Diameter	100mm
Orientation (c->m)	+0.2
Backside Roughness	Fine Ground

AlN

Orientation (major flat)	m-plane (AlN)
.....	
Thickness (measurement by whitelight)	
Avg	0.5 μm \pm 0.05 μm
(σ /Avg)	< 2%
.....	
Crystal Quality (FWHM)	
[002] XRD Linewidth	< 100 arcsec
[102] XRD Linewidth	< 300 arcsec
.....	
Transmission	>85% (@ 280 nm)
.....	
Exclusion Zone	3 mm
.....	
Surface Morphology	
AFM (R_z)	< 1 nm